

***Sanja M. Aleksić***

LIST OF PUBLICATIONS

Publications in International Journals

1. **S. M. Aleksić**, A. B. Jakšić, M. M. Pejović, „Repeating of positive and negative high electric field stress and corresponding thermal post-stress annealing of the n-channel power VDMOSFETs“, Solid-State Electronics, accepted for publication.
2. A. Jakšić, M. Pejović, G. Ristić, **S. Raković**, ”Latent interface-trap generation in commercial power VDMOSFETs”, IEEE Trans. Nucl. Sci., Vol. 45, No. 3, pp. 1365-1371, 1998.

Contributed Papers in International Conferences

1. A. Jakšić, M. Pejović, G. Ristić, **S. Raković**, ”Latent interface-trap generation in commercial power VDMOSFETs, *4<sup>th</sup> European Confer. radiations and their effects on devices and systems (RADECS 97)*, Abstracts, pp. A.5-A.6, 1997.